

Supporting information:

**Self-assembled metal-oxo clusters for sensitive and low-powered
ultraviolet photodetectors**

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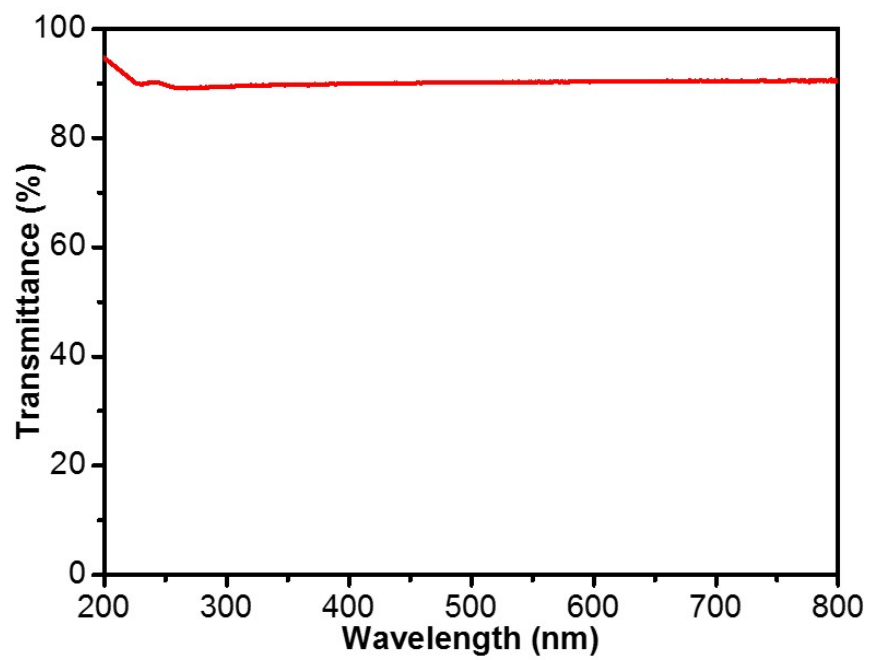


Figure S1. UV-Vis spectrum of PEI thin film-coated quartz.

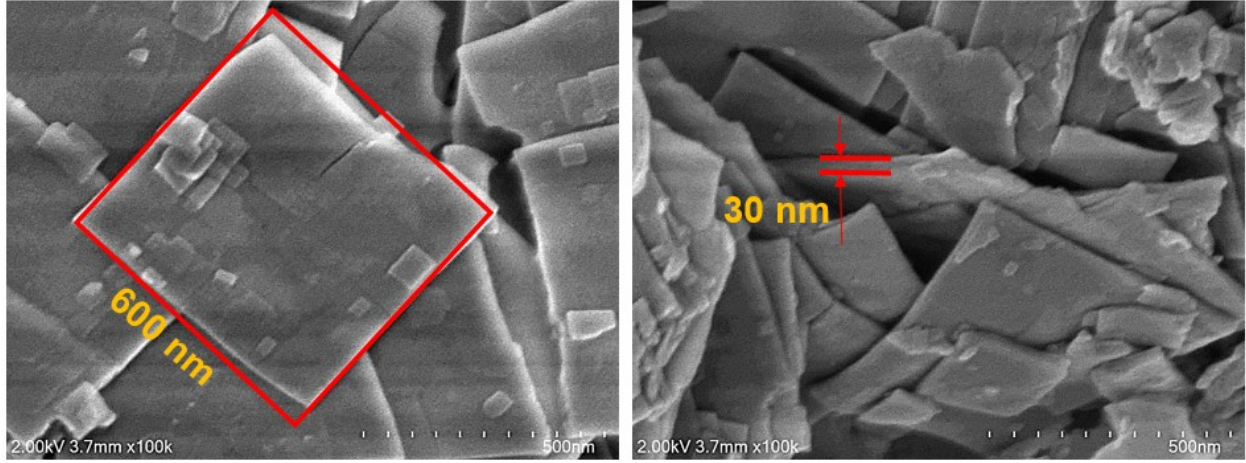


Figure S2. Dimension and thickness of ZOC flake determined from SEM image.

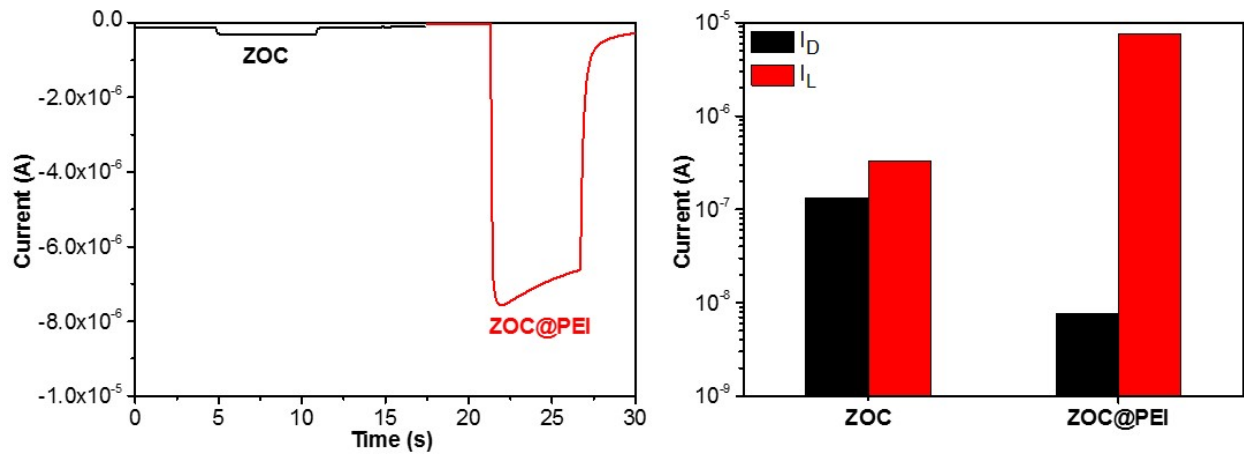


Figure S3. Photoresponses, dark current (I_D) and current-in-light (I_L) of ZOC and ZOC@PEI devices at 0 V under 254-nm UV light (power intensity of $445 \mu\text{W}$).

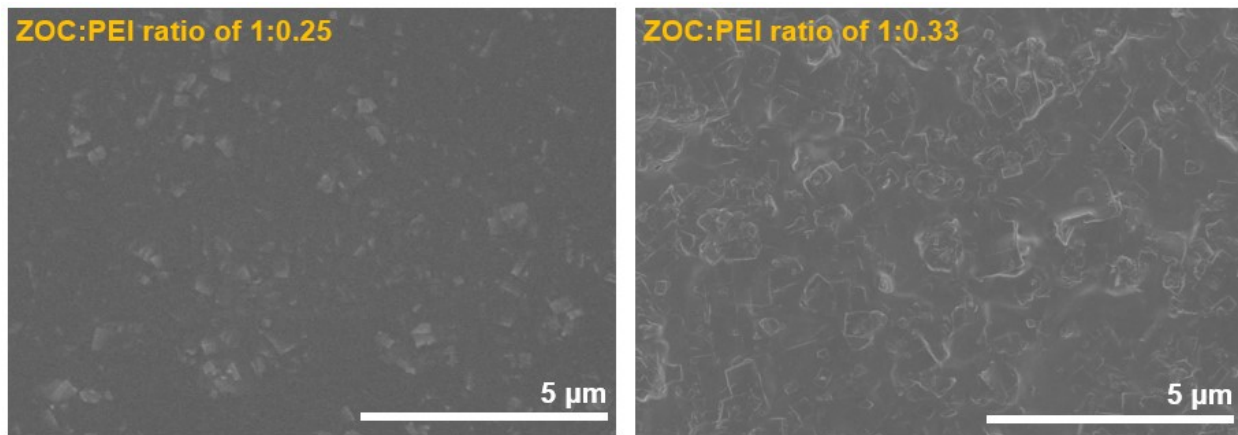


Figure S4. SEM images of ZOC@PEI films (at ZOC:PEI ratios of 1:0.25 and 1:0.33).